

Notice of References Cited	Application/Control No. 10/060,945		Applicant(s)/Patent Under Reexamination CARRICK ET AL.	
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	U	Sankawa, I. et al. "Fault location technique for in-service branched optical fiber networks." IEEE Photonics Technology Letters, Vol. 2, No. 10, October 1990: 766-768.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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